



# **Colloquium on Solid-State Physics**

**Thursday, November 29, 2018**

**17:15**

**Lecture Theatre III**

**Physics Department, TU München**

**Towards in-situ defect characterization  
in semiconductor devices using CMOS-  
integrated magnetic resonance detectors**

**Prof. Dr. Jens Anders  
Institute of Smart Sensors  
University of Stuttgart  
Germany**